

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/037,271	HUFFER, SCOTT W	
Examiner	Art Unit	
Ren L. Yan	2854	

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Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMF	